

ANALOG Two Selectable Inputs, 10 LVPECL Outputs, Sign Clock Format Buffage **SiGe Clock Fanout Buffer**

ADCLK950 **Data Sheet**

FEATURES

2 selectable differential inputs 4.8 GHz operating frequency 75 fs rms broadband random jitter **On-chip input terminations** 3.3 V power supply

APPLICATIONS

Low jitter clock distribution Clock and data signal restoration Level translation Wireless communications Wired communications Medical and industrial imaging ATE and high performance instrumentation

GENERAL DESCRIPTION

The ADCLK950 is an ultrafast clock fanout buffer fabricated on the Analog Devices, Inc., proprietary XFCB3 silicon germanium (SiGe) bipolar process. This device is designed for high speed applications requiring low jitter.

The device has two selectable differential inputs via the IN_SEL control pin. Both inputs are equipped with center tapped, differential, 100 Ω on-chip termination resistors. The inputs accept dc-coupled LVPECL, CML, 3.3 V CMOS (single-ended), and ac-coupled 1.8 V CMOS, LVDS, and LVPECL inputs. A V_{REF}x pin is available for biasing ac-coupled inputs.

The ADCLK950 features 10 full-swing emitter coupled logic (ECL) output drivers. For LVPECL (positive ECL) operation, bias V_{CC} to the positive supply and V_{EE} to ground. For ECL operation, bias V_{CC} to ground and V_{EE} to the negative supply.

The output stages are designed to directly drive 800 mV each side into 50 Ω terminated to V_{CC} – 2 V for a total differential output swing of 1.6 V.

The ADCLK950 is available in a 40-lead LFCSP and specified for operation over the standard industrial temperature range of -40°C to +85°C.

FUNCTIONAL BLOCK DIAGRAM

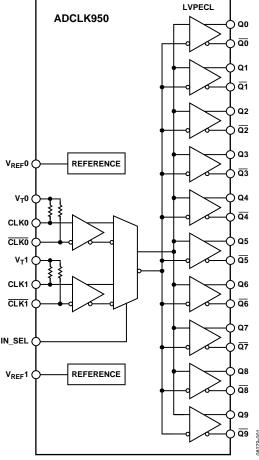


Figure 1.

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REVISION HISTORY

8/2016—Rev. A to Rev. B

| Changed CP-40-8 to CP-40-16 | Throughout |
|---------------------------------|------------|
| Changes to Figure 2 and Table 7 | 6 |
| Updated Outline Dimensions | 12 |
| Changes to Ordering Guide | 12 |

6/2010—Rev. 0 to Rev. A

7/2009—Revision 0: Initial Version

SPECIFICATIONS

ELECTRICAL CHARACTERISTICS

Typical (Typ column) values are given for $V_{CC} - V_{EE} = 3.3 \text{ V}$ and $T_A = 25^{\circ}\text{C}$, unless otherwise noted. Minimum (Min column) and maximum (Max column) values are given over the full $V_{CC} - V_{EE} = 3.3 \text{ V} \pm 10\%$ and $T_A = -40^{\circ}\text{C}$ to $+85^{\circ}\text{C}$ variation, unless otherwise noted.

Table 1. Clock Inputs and Outputs

| Parameter | Symbol | Min | Тур | Max | Unit | Test Conditions/Comments |
|------------------------------|-----------------|------------------------|------------------|-----------------|-------|---|
| DC INPUT CHARACTERISTICS | | | | | | |
| Input Common Mode Voltage | V_{ICM} | V _{EE} + 1.5 | | $V_{CC} - 0.1$ | V | |
| Input Differential Range | V _{ID} | 0.4 | | 3.4 | V p-p | ±1.7 V between input pins |
| Input Capacitance | C _{IN} | | 0.4 | | pF | |
| Input Resistance | | | | | | |
| Single-Ended Mode | | | 50 | | Ω | |
| Differential Mode | | | 100 | | Ω | |
| Common Mode | | | 50 | | kΩ | Open V _⊤ x |
| Input Bias Current | | | 20 | | μΑ | |
| Hysteresis | | | 10 | | mV | |
| DC OUTPUT CHARACTERISTICS | | | | | | |
| Output Voltage High Level | V _{OH} | V _{CC} – 1.26 | | $V_{CC} - 0.76$ | V | 50Ω to (V _{CC} $- 2.0 V$) |
| Output Voltage Low Level | V _{OL} | V _{CC} – 1.99 | | $V_{CC} - 1.54$ | V | 50Ω to (V _{CC} $- 2.0 V$) |
| Output Voltage, Single Ended | V _o | 610 | | 960 | mV | $V_{OH} - V_{OL}$, output static |
| Reference Voltage | V_{REF} | | | | | |
| Output Voltage | | | $(V_{CC} + 1)/2$ | | V | –500 μA to +500 μA |
| Output Resistance | | | 235 | | Ω | |

Table 2. Timing Characteristics

| Parameter | Symbol | Min | Тур | Max | Unit | Test Conditions/Comments |
|---------------------------------------|-----------------|-----|------|-----|--------|--|
| AC PERFORMANCE | | | | | | |
| Maximum Output Frequency | | 4.5 | 4.8 | | GHz | See Figure 4 for differential output voltage vs. frequency, >0.8 V differential output swing |
| Output Rise Time | t _R | 40 | 75 | 90 | ps | 20% to 80% measured differentially |
| Output Fall Time | t _F | 40 | 75 | 90 | ps | |
| Propagation Delay | t _{PD} | 175 | 210 | 245 | ps | $V_{ICM} = 2 \text{ V}, V_{ID} = 1.6 \text{ V p-p}$ |
| Temperature Coefficient | | | 50 | | fs/°C | |
| Output-to-Output Skew ¹ | | | 9 | 28 | ps | |
| Part-to-Part Skew | | | | 45 | ps | $V_{ID} = 1.6 \text{ V p-p}$ |
| Additive Time Jitter | | | | | | |
| Integrated Random Jitter | | | 28 | | fs rms | BW = 12 kHz – 20 MHz, CLK = 1 GHz |
| Broadband Random Jitter ² | | | 75 | | fs rms | $V_{ID} = 1.6 \text{ V p-p, } 8 \text{ V/ns, } V_{ICM} = 2 \text{ V}$ |
| Crosstalk-Induced Jitter ³ | | | 90 | | fs rms | |
| CLOCK OUTPUT PHASE NOISE | | | | | | |
| Absolute Phase Noise | | | | | | Input slew rate > 1 V/ns (see Figure 11, the phase noise plot, for more details) |
| $f_{IN} = 1 \text{ GHz}$ | | | -119 | | dBc/Hz | @100 Hz offset |
| | | | -134 | | dBc/Hz | @1 kHz offset |
| | | | -145 | | dBc/Hz | @10 kHz offset |
| | | | -150 | | dBc/Hz | @100 kHz offset |
| | | | -150 | | dBc/Hz | >1 MHz offset |

¹ The output skew is the difference between any two similar delay paths while operating at the same voltage and temperature.

² Measured at the rising edge of the clock signal; calculated using the SNR of the ADC method.
³ This is the amount of added jitter measured at the output while two related, asynchronous, differential frequencies are applied to the inputs.

Table 3. Input Select Control Pin

| Parameter | Symbol | Min | Тур | Max | Unit |
|-----------------|-----------------|-----------------------|-----|-----------------|------|
| Logic 1 Voltage | V _{IH} | V _{CC} - 0.4 | | V _{cc} | V |
| Logic 0 Voltage | V _{IL} | V_{EE} | | 1 | V |
| Logic 1 Current | I _{IH} | | | 100 | μΑ |
| Logic 0 Current | I _{IL} | | | 0.6 | mA |
| Capacitance | | | 2 | | pF |

Table 4. Power

| Parameter | Symbol | Min | Тур | Max | Unit | Test Conditions/Comments |
|--|-------------------|------|-----|------|------|--|
| POWER SUPPLY | | | | | | |
| Supply Voltage Requirement | $V_{CC} - V_{EE}$ | 2.97 | | 3.63 | V | 3.3 V + 10% |
| Power Supply Current | | | | | | Static |
| Negative Supply Current | I _{VEE} | | 106 | 130 | mA | $V_{CC} - V_{EE} = 3.3 \text{ V} \pm 10\%$ |
| Positive Supply Current | I _{vcc} | | 346 | 390 | mA | $V_{CC} - V_{EE} = 3.3 \text{ V} \pm 10\%$ |
| Power Supply Rejection ¹ | PSR_{VCC} | | <3 | | ps/V | $V_{CC} - V_{EE} = 3.3 \text{ V} \pm 10\%$ |
| Output Swing Supply Rejection ² | PSR_{VCC} | | 28 | | dB | $V_{CC} - V_{EE} = 3.3 \text{ V} \pm 10\%$ |

 $^{^1}$ Change in t_{PD} per change in $V_{CC}.$ 2 Change in output swing per change in $V_{CC}.$

ABSOLUTE MAXIMUM RATINGS

Table 5.

| Parameter | Rating |
|---|---|
| Supply Voltage | |
| $V_{CC} - V_{EE}$ | 6 V |
| Input Voltage | |
| CLK0, CLK1, CLK0, CLK1, IN_SEL | $V_{EE} - 0.5 \text{ V to}$ $V_{CC} + 0.5 \text{ V}$ |
| CLK0, CLK1, $\overline{\text{CLK0}}$, $\overline{\text{CLK1}}$ to $V_T x$ Pin (CML, | ±40 mA |
| LVPECL Termination) | |
| CLK0, CLK1 to CLK0, CLK1 | ±1.8 V |
| Input Termination, $V_T x$ to CLK0, CLK1, $\overline{\text{CLK0}}$, and $\overline{\text{CLK1}}$ | ±2 V |
| Maximum Voltage on Output Pins | $V_{CC} + 0.5 V$ |
| Maximum Output Current | 35 mA |
| Voltage Reference (V _{REF} x) | V_{CC} to V_{EE} |
| Operating Temperature Range | |
| Ambient | −40°C to +85°C |
| Junction | 150°C |
| Storage Temperature Range | −65°C to +150°C |

Stresses at or above those listed under Absolute Maximum Ratings may cause permanent damage to the product. This is a stress rating only; functional operation of the product at these or any other conditions above those indicated in the operational section of this specification is not implied. Operation beyond the maximum operating conditions for extended periods may affect product reliability.

DETERMINING JUNCTION TEMPERATURE

To determine the junction temperature on the application printed circuit board (PCB), use the following equation:

$$T_I = T_{CASE} + (\Psi_{IT} \times P_D)$$

where:

 T_I is the junction temperature (°C).

 $T_{\it CASE}$ is the case temperature (°C) measured by the customer at the top center of the package.

 Ψ_{IT} is from Table 6.

 P_D is the power dissipation.

Values of θ_{JA} are provided for package comparison and PCB design considerations. θ_{JA} can be used for a first-order approximation of T_I by the equation

$$T_I = T_A + (\theta_{IA} \times P_D)$$

where T_A is the ambient temperature (°C).

Values of θ_{JB} are provided in Table 6 for package comparison and PCB design considerations.

ESD CAUTION



ESD (electrostatic discharge) sensitive device. Charged devices and circuit boards can discharge without detection. Although this product features patented or proprietary protection circuitry, damage may occur on devices subjected to high energy ESD. Therefore, proper ESD precautions should be taken to avoid performance degradation or loss of functionality.

THERMAL PERFORMANCE

Table 6.

| Parameter | Symbol | Description | Value ¹ | Unit |
|---|----------------|--------------------------------|--------------------|------|
| Junction-to-Ambient Thermal Resistance | θ_{JA} | | | |
| Still Air | | Per JEDEC JESD51-2 | | |
| 0 m/sec Air Flow | | | 46.1 | °C/W |
| Moving Air | θ_{JMA} | Per JEDEC JESD51-6 | | |
| 1 m/sec Air Flow | | | 40.3 | °C/W |
| 2.5 m/sec Air Flow | | | 36.2 | °C/W |
| Junction-to-Board Thermal Resistance | θ_{JB} | | | |
| Moving Air | | Per JEDEC JESD51-8 | | |
| 1 m/sec Air Flow | | | 28.7 | °C/W |
| Junction-to-Case Thermal Resistance | θ_{JC} | | | |
| Moving Air | | Per MIL-STD 883, Method 1012.1 | | |
| Die-to-Heatsink | | | 8.3 | °C/W |
| Junction-to-Top-of-Package Characterization Parameter | $\Psi_{ m JT}$ | | | |
| Still Air | | Per JEDEC JESD51-2 | | |
| 0 m/sec Air Flow | | | 0.6 | °C/W |

¹ Results are from simulations. The PCB is a JEDEC multilayer type. Thermal performance for actual applications requires careful inspection of the conditions in the application to determine if they are similar to those assumed in these calculations.

PIN CONFIGURATION AND FUNCTION DESCRIPTIONS

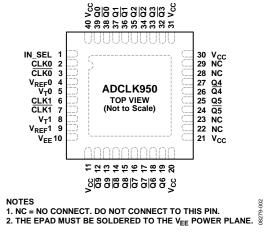


Figure 2. Pin Configuration

Table 7. Pin Function Descriptions

| Pin No. | Mnemonic | Description |
|---------------------------|--------------------|---|
| 1 | IN_SEL | Input Select. Logic 0 selects CLK0 and CLK0 inputs. Logic 1 selects CLK1 and CLK1 inputs. |
| 2 | CLK0 | Differential Input (Positive) 0. |
| 3 | CLK0 | Differential Input (Negative) 0. |
| 4 | V _{REF} 0 | Reference Voltage. Reference voltage for biasing ac-coupled CLK0 and CLK0 inputs. |
| 5 | V _T 0 | Center Tap. Center tap of a 100 Ω input resistor for CLK0 and $\overline{\text{CLK0}}$ inputs. |
| 6 | CLK1 | Differential Input (Positive) 1. |
| 7 | CLK1 | Differential Input (Negative) 1. |
| 8 | V _T 1 | Center Tap. Center tap of a 100 Ω input resistor for CLK1 and $\overline{\text{CLK1}}$ inputs. |
| 9 | V _{REF} 1 | Reference Voltage. Reference voltage for biasing ac-coupled CLK1 and CLK1 inputs. |
| 10 | V _{EE} | Negative Supply Pin. |
| 11, 20, 21, 30, 31, 40 | V _{cc} | Positive Supply Pin. |
| 12, 13 | Q 9, Q9 | Differential LVPECL Outputs. |
| 14, 15 | Q 8, Q8 | Differential LVPECL Outputs. |
| 16, 17 | Q7 , Q7 | Differential LVPECL Outputs. |
| 18, 19 | Q6 , Q6 | Differential LVPECL Outputs. |
| 22, 23, 28, 29 | NC | No Connection |
| 24, 25 | Q5, Q5 | Differential LVPECL Outputs. |
| 26, 27 | Q4 , Q4 | Differential LVPECL Outputs. |
| 32, 33 | Q 3, Q3 | Differential LVPECL Outputs. |
| 34, 35 | Q2, Q2 | Differential LVPECL Outputs. |
| 36, 37 | Q 1, Q1 | Differential LVPECL Outputs. |
| 38, 39 | Q 0, Q0 | Differential LVPECL Outputs. |
| | EPAD | Exposed Pad. The EPAD must be soldered to the V_{EE} power plane. |

TYPICAL PERFORMANCE CHARACTERISTICS

 $V_{CC} = 3.3 \text{ V}, V_{EE} = 0 \text{ V}, V_{ICM} = V_{REF}x, T_A = 25^{\circ}\text{C}, clock outputs terminated at 50 }\Omega$ to $V_{CC} - 2 \text{ V}, unless otherwise noted.}$

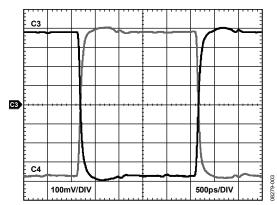


Figure 3. LVPECL Output Waveform @ 200 MHz

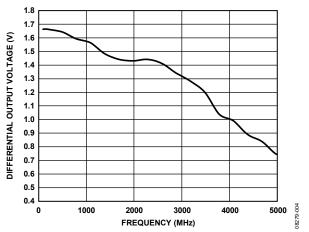


Figure 4. Differential Output Voltage vs. Frequency, $V_{ID} > 1.1 \text{ V p-p}$

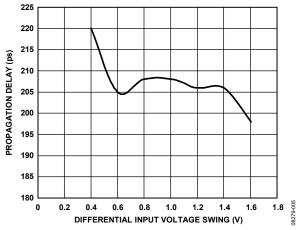


Figure 5. Propagation Delay vs. Differential Input Voltage

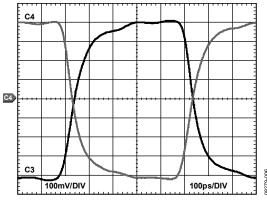


Figure 6. LVPECL Output Waveform @ 1000 MHz

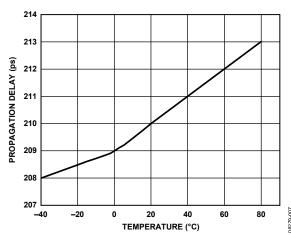


Figure 7. Propagation Delay vs. Temperature, $V_{ID} = 1.6 \text{ V p-p}$

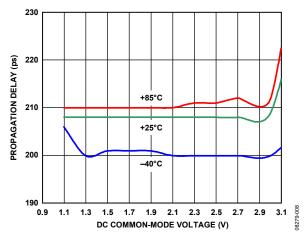


Figure 8. Propagation Delay vs. DC Common-Mode Voltage vs. Temperature, Input Slew Rate > 25 V/ns

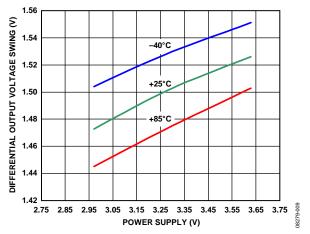


Figure 9. Differential Output Voltage Swing vs. Power Supply Voltage vs. Temperature, $V_{\rm ID}$ = 1.6 V p-p

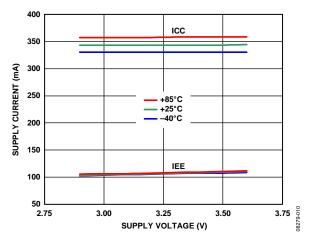


Figure 10. Power Supply Current vs. Power Supply Voltage vs. Temperature, All Outputs Loaded (50 Ω to V_{CC} – 2 V)

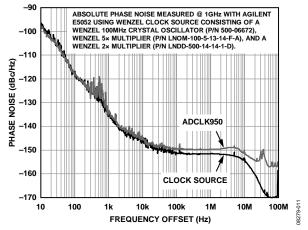


Figure 11. Absolute Phase Noise Measured @1 GHz

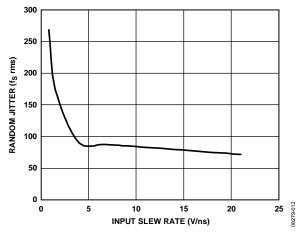


Figure 12. RMS Random Jitter vs. Input Slew Rate, V_{ID} Method

FUNCTIONAL DESCRIPTION CLOCK INPUTS

The ADCLK950 accepts a differential clock input from one of two inputs and distributes the selected clock to all 10 LVPECL outputs. The maximum specified frequency is the point at which the output voltage swing is 50% of the standard LVPECL swing (see Figure 4). See the functional block diagram (Figure 1) and the General Description section for more clock input details. See Figure 19 through Figure 23 for various clock input termination schemes.

Output jitter performance is degraded by an input slew rate below 4 V/ns, as shown in Figure 12. The ADCLK950 is specifically designed to minimize added random jitter over a wide input slew rate range. Whenever possible, clamp excessively large input signals with fast Schottky diodes because attenuators reduce the slew rate. Input signal runs of more than a few centimeters should be over low loss dielectrics or cables with good high frequency characteristics.

CLOCK OUTPUTS

The specified performance necessitates using proper transmission line terminations. The LVPECL outputs of the ADCLK950 are designed to directly drive 800 mV into a 50 Ω cable or into microstrip/stripline transmission lines terminated with 50 Ω referenced to $V_{\rm CC}-2$ V, as shown in Figure 14. The LVPECL output stage is shown in Figure 13. The outputs are designed for best transmission line matching. If high speed signals must be routed more than a centimeter, either the microstrip or the stripline technique is required to ensure proper transition times and to prevent excessive output ringing and pulse width dependent propagation delay dispersion.

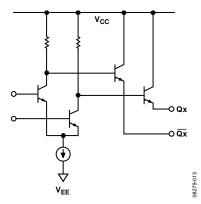


Figure 13. Simplified Schematic Diagram of the LVPECL Output Stage

Figure 14 through Figure 17 depict various LVPECL output termination schemes. When dc-coupled, $\rm V_{\rm S}$ of the receiving buffer should match VS_DRV.

The venin-equivalent termination uses a resistor network to provide 50 Ω termination to a dc voltage that is below $V_{\rm OL}$ of the LVPECL driver. In this case, VS_DRV on the ADCLK950 should equal $V_{\rm S}$ of the receiving buffer. Although the resistor combination shown (in Figure 15) results in a dc bias point of VS_DRV – 2 V, the actual common-mode voltage is VS_DRV – 1.3 V because there is additional current flowing from the ADCLK950 LVPECL driver through the pull-down resistor.

LVPECL Y-termination is an elegant termination scheme that uses the fewest components and offers both odd- and even-mode impedance matching. Even-mode impedance matching is an important consideration for closely coupled transmission lines at high frequencies. Its main drawback is that it offers limited flexibility for varying the drive strength of the emitter follower LVPECL driver. This can be an important consideration when driving long trace lengths but is usually not an issue.

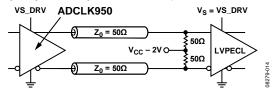


Figure 14. DC-Coupled, 3.3 V LVPECL

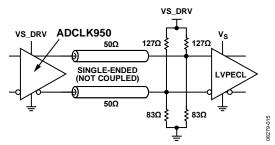


Figure 15. DC-Coupled, 3.3 V LVPECL Far-End Thevenin Termination

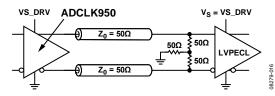


Figure 16. DC-Coupled, 3.3 V LVPECL Y-Termination

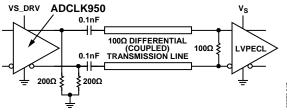


Figure 17. AC-Coupled, LVPECL with Parallel Transmission Line

CLOCK INPUT SELECT (IN_SEL) SETTINGS

A Logic 0 on the IN_SEL pin selects the Input CLK0 and Input CLK0. A Logic 1 on the IN_SEL pin selects Input CLK1 and Input CLK1.

PCB LAYOUT CONSIDERATIONS

The ADCLK950 buffer is designed for very high speed applications. Consequently, high speed design techniques must be used to achieve the specified performance. It is critically important to use low impedance supply planes for both the negative supply (V_{EE}) and the positive supply (V_{CC}) planes as part of a multilayer board. Providing the lowest inductance return path for switching currents ensures the best possible performance in the target application.

The following references to the GND plane assume that the $V_{\mbox{\tiny EE}}$ power plane is grounded for LVPECL operation. Note that for ECL operation, the $V_{\mbox{\tiny CC}}$ power plane becomes the ground plane.

It is also important to adequately bypass the input and output supplies. Place a 1 μF electrolytic bypass capacitor within several inches of each $V_{\rm CC}$ power supply pin to the GND plane. In addition, place multiple high quality 0.001 μF bypass capacitors as close as possible to each of the $V_{\rm CC}$ supply pins, and connect the capacitors to the GND plane with redundant vias. Carefully select high frequency bypass capacitors for minimum inductance and ESR. To improve the effectiveness of the bypass at high frequencies, minimize parasitic layout inductance. Also, avoid discontinuities along input and output transmission lines that can affect jitter performance.

In a 50 Ω environment, input and output matching have a significant impact on performance. The buffer provides internal 50 Ω termination resistors for both CLKx and $\overline{\text{CLKx}}$ inputs. Normally, the return side is connected to the reference pin that is provided. Carefully bypass the termination potential using ceramic capacitors to prevent undesired aberrations on the input signal due to parasitic inductance in the termination

return path. If the inputs are dc-coupled to a source, take care to ensure that the pins are within the rated input differential and common-mode ranges.

If the return is floated, the device exhibits a 100 Ω cross termination, but the source must then control the common-mode voltage and supply the input bias currents.

There are ESD/clamp diodes between the input pins to prevent the application from developing excessive offsets to the input transistors. ESD diodes are not optimized for best ac performance. When a clamp is required, it is recommended that appropriate external diodes be used.

Exposed Metal Paddle

The exposed metal paddle on the ADCLK950 package is both an electrical connection and a thermal enhancement. For the device to function properly, the paddle must be properly attached to the $V_{\rm EE}$ power plane.

When properly mounted, the ADCLK950 also dissipates heat through its exposed paddle. The PCB acts as a heat sink for the ADCLK950. The PCB attachment must provide a good thermal path to a larger heat dissipation area. This requires a grid of vias from the top layer down to the $V_{\rm EE}$ power plane (see Figure 18). The ADCLK950 evaluation board (ADCLK950/PCBZ) provides an example of how to attach the part to the PCB.

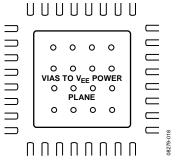


Figure 18. PCB Land for Attaching Exposed Paddle

INPUT TERMINATION OPTIONS

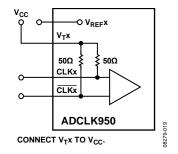


Figure 19. DC-Coupled CML Input Termination

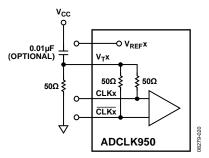


Figure 20. DC-Coupled LVPECL Input Termination

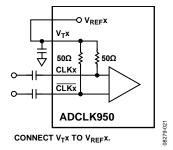
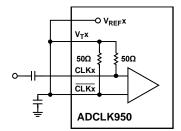


Figure 21. AC-Coupled Input Termination, Such as LVDS and LVPECL



CONNECT $V_{T}x$, $V_{REF}x$, and \overline{CLKx} . Place a Bypass capacitor from $V_{T}x$ to ground. Alternatively, $V_{T}x$, $V_{REF}x$, and clkx can be connected, giving a cleaner layout and a 180° phase shift.

Figure 22. AC-Coupled Single-Ended Input Termination

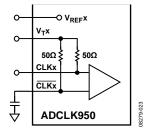


Figure 23. DC-Coupled 3.3 V CMOS Input Termination

OUTLINE DIMENSIONS

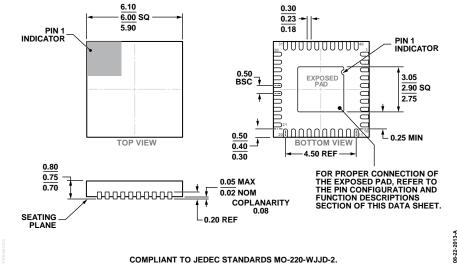


Figure 24. 40-Lead Lead Frame Chip Scale Package [LFCSP] 6 mm × 6 mm Body and 0.75 mm Package Height (CP-40-16) Dimensions shown in millimeters

ORDERING GUIDE

| Model ¹ | Temperature Range | Package Description | Package Option |
|--------------------|-------------------|---|----------------|
| ADCLK950BCPZ | −40°C to +85°C | 40-Lead Lead Frame Chip Scale Package [LFCSP] | CP-40-16 |
| ADCLK950BCPZ-REEL7 | -40°C to +85°C | 40-Lead Lead Frame Chip Scale Package [LFCSP] | CP-40-16 |
| ADCLK950/PCBZ | | Evaluation Board | |

¹ Z = RoHS Compliant Part.